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APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY DOCKET NO.	DRAWINGS	TOT CLAIMS	IND CLAIMS
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FILING RECEIPT



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Continuing Data as Claimed by Applicant

Foreign Applications

JAPAN 11-246582 08/31/1999
JAPAN 2000-252881 08/23/2000

If Required, Foreign Filing License Granted 10/17/2000

Title

Semiconductor substrate and its fabrication method

Preliminary Class

257

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